Hydrogen Peroxide, 30%
Electronic Grade
(Stabilized)

Part of AVANTOR™ PERFORMANCE MATERIALS

Material No.: 2204-01
Batch No.: 0000105670
Manufactured Date: 2015/02/25
Expiration Date: 2016/08/25

Certificate of Analysis

Test	Specification	Result
Assay (H_2O_2)	30.0 - 32.0 %	31.1
Color (APHA)	<= 10	5
Free Acid (µeq/g)	<= 0.2	< 0.2
Residue after Evaporation	<= 15 ppm	< 5
Ammonium (NH_4)	<= 3 ppm	< 3
Chloride (Cl)	<= 2 ppm	< 2
Nitrate (NO_3)	<= 2 ppm	< 1
Phosphate (PO_4)	<= 2 ppm	< 2
ACS - Sulfate (SO_4)	<= 5 ppm	< 5
Trace Impurities - Aluminum (Al)	<= 200.0 ppb	< 5.0
Trace Impurities - Antimony (Sb)	<= 10.0 ppb	< 1.0
Trace Impurities - Arsenic (As)	<= 10.0 ppb	< 2.0
Arsenic and Antimony (as As)	<= 10 ppb	< 10
Trace Impurities - Barium (Ba)	<= 20.0 ppb	< 1.0
Trace Impurities - Beryllium (Be)	<= 10.0 ppb	< 1.0
Trace Impurities - Bismuth (Bi)	<= 20.0 ppb	< 10.0
Trace Impurities - Boron (B)	<= 10.0 ppb	< 5.0
Trace Impurities - Cadmium (Cd)	<= 10.0 ppb	< 1.0
Trace Impurities - Calcium (Ca)	<= 50.0 ppb	< 1.0
Trace Impurities - Chromium (Cr)	<= 20.0 ppb	< 1.0
Trace Impurities - Cobalt (Co)	<= 10.0 ppb	< 1.0
Trace Impurities - Copper (Cu)	<= 10.0 ppb	< 1.0
Trace Impurities - Gallium (Ga)	<= 20.0 ppb	< 1.0
Trace Impurities - Germanium (Ge)	<= 10.0 ppb	< 10.0

Test	Specification	Result
Trace Impurities - Gold (Au)	<= 10.0 ppb	< 5.0
Heavy Metals (as Pb)	<= 500 ppb	< 250
Trace Impurities - Iron (Fe)	<= 50.0 ppb	< 1.0
Trace Impurities - Lead (Pb)	<= 10.0 ppb	< 10.0
Trace Impurities - Lithium (Li)	<= 10.0 ppb	< 1.0
Trace Impurities - Magnesium (Mg)	<= 10.0 ppb	< 1.0
Trace Impurities - Manganese (Mn)	<= 10.0 ppb	< 1.0
Trace Impurities - Molybdenum (Mo)	<= 10.0 ppb	< 5.0
Trace Impurities - Nickel (Ni)	<= 10.0 ppb	< 5.0
Trace Impurities - Niobium (Nb)	<= 10.0 ppb	< 1.0
Trace Impurities - Potassium (K)	<= 600.0 ppb	215.8
Trace Impurities - Silicon (Si)	<= 100.0 ppb	< 10.0
Trace Impurities - Silver (Ag)	<= 10.0 ppb	< 1.0
Trace Impurities - Sodium (Na)	<= 500.0 ppb	< 5.0
Trace Impurities - Strontium (Sr)	<= 10.0 ppb	< 1.0
Trace Impurities - Tantalum (Ta)	<= 10.0 ppb	< 5.0
Trace Impurities - Thallium (Tl)	<= 50.0 ppb	< 5.0
Trace Impurities - Tin (Sn)	<= 1000.0 ppb	303.1
Trace Impurities - Titanium (Ti)	<= 10.0 ppb	< 1.0
Trace Impurities - Vanadium (V)	<= 10.0 ppb	< 1.0
Trace Impurities - Zinc (Zn)	<= 50.0 ppb	< 1.0
Trace Impurities - Zirconium (Zr)	<= 10.0 ppb	< 1.0

For Microelectronic Use

Country of Origin:	US
Packaging Site:	Paris Mfg Ctr & DC

ISO
Phillipsburg, NJ 9001:2008, 14001:2004, FSSC 22000
Paris, KY 9001:2008
Mexico City, Mexico 9001:2008
Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003
Gliwice, Poland 9001:2008, 17025:2005
Selangor, Malaysia 9001:2008
Dehradun, India, 9001:2008, 14001:2004, 13485:2003
Mumbai, India, 9001:2008, 17025:2005
Panoli, India 9001:2008

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